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Effect of Sn-doping on the electrochemical behaviour of TiO₂ nanotubes as potential negative electrode materials for 3D Li-ion micro batteries

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HIGHLIGHTS

- ▶ Sn-doped TiO₂ nanotubes were fabricated by anodization of sputtered Ti—Sn thin films.
- ▶ The Sn-doped TiO₂nts can be used as anodes for 3D Li-ion micro batteries.
- ► The electrochemical performance of Sn-doped TiO₂nts was better than simple TiO₂nts.
- ▶ The improved performance is related to enhanced lithium diffusivity with Sn doping.
- ▶ This synthesis approach is extendable for Fe/Sb/Nb-doping of TiO₂ nanotubes.

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ABSTRACT

Self-organized Sn-doped TiO₂ nanotubes were fabricated by anodization of co-sputtered Ti—Sn thin films in a glycerol electrolyte containing NH₄F. The Sn-doped TiO₂nts were studied in terms of composition, morphology and structure by scanning electron microscopy, X-ray diffraction, X-ray photoelectron spectroscopy and ¹¹⁹Sn Mössbauer spectroscopy. The electrochemical behaviour of the Sn-doped TiO₂nts was evaluated in Li test cells as a possible negative electrode for 3D Li-ion micro batteries. The Sn-doped TiO₂nts delivered much higher capacity values compared to simple TiO₂nts. The outstanding electrochemical behaviour is proposed to be related to the enhanced lithium diffusivity evidenced with Cottrell plots, and the rutile-type structure imparted with the Sn doping.

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1. Introduction

The advent of modern microelectronic devices challenges scientists to investigate high-performance micro batteries. All-solid-state (thin-film) micro batteries are integrated into microelectronic circuit boards to deliver low energy to various devices such as hearing aids, medical implants, remote sensors, RFID tags etc [1-3].

To date, these micro batteries are based on a parallel (or pseudoparallel) or a sandwich configuration of planar electrodes separated by a solid electrolyte. This planar configuration leads to relatively low volumetric energy and power densities. However, the miniaturization of recent electronic devices requires higher volumetric energy densities in addition to size diminution (on the order of 0.1 cm³). In this context, the development of three-dimensional (3D) thin-film micro batteries represents a viable alternative [4,5]. The 3D design will ensure that anode and cathode materials have (active) surface areas exposed in three dimensions — exploiting the out-of-plane dimension instead of just the conventional in-plane surface. Nano-structuration of electrode materials is one of the most promising approaches to realize this 3D paradigm of micro batteries [6]. Not only is the reduction of the areal footprint crucial, new and highly performing anode, cathode and electrolyte materials are also imperative for high performance and low manufacturing cost.

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Actually, the negative electrode material of thin-film micro batteries is of a great concern. Almost all thin-film micro batteries utilize metallic lithium anode that has a low melting point and a strong reactivity. Furthermore, an expensive packaging technology is always required due to the lithium anode [7,8]. Recently, significant attempts are being made to fully adopt the "Li-ion" or the "rocking-chair" concept in the design of lithium-based micro batteries [1.9]. This implies combining cathode materials such as LiCoO₂, LiMn₂O₄ or LiFePO₄ [10–12] with the wide range of possible anode materials proven to react reversibly with lithium either by insertion [13,14], alloying [9,15–18] or conversion [19–22]. Cathode materials such as V_2O_5 and TiO_xS_v are of considerable interest particularly with a lithiated anode material to maintain the 'Li-ion' concept [8,23–25]. Among all the potential anode materials, TiO₂ nanotubes (TiO₂nts) possess a spectacular characteristic for the design of 3D Li-ion micro batteries [26,27]. Besides the selforganized (3D) nano-architecture, TiO2 nanotubes exhibit very good capacity retention particularly at moderately high kinetic rates [13,14,27-29]. As TiO₂ (anatase or rutile) effectively inserts only 0.5 Li⁺ per formula unit, corresponding to a theoretical capacity of 168 mAh g⁻¹ [14,30,31], interest has risen recently to improve the overall performance of TiO₂ nanotubes for the design of high-performance 3D Li-ion micro batteries. TiO2 being a semiconductor, selective doping by aliovalent or homovalent substitution of Ti affects the intrinsic electrical properties to some extent.

In this work, TiO₂ nanotubes were doped with Sn⁴⁺ by potentiostatic anodization of Ti—Sn thin films which were produced by co-sputtering of titanium and tin targets. X-ray diffraction, X-ray photoelectron spectroscopy and ¹¹⁹Sn Mössbauer spectroscopy were employed to help ascertain the quality of the doping operation. The effects of Sn⁴⁺ doping on the morphology and the electronic properties of TiO₂ nanotubes were investigated. Finally, the impact of Sn⁴⁺ doping on the electrochemical behaviour of TiO₂ nanotubes as anodes for 3D Li-ion micro batteries was evaluated in lithium test cells.

2. Experiment

Metallic targets (Ti and Sn, 99.9% pure) were supplied by Sigma-Aldrich. For the co-sputtering, the Ti and Sn targets were cut into the right proportions (considering the sputtering rates of Ti and Sn in relation to the anticipated thin film composition), cleaned and assembled in a target holder with the aid of a silver paste. The target, after drying overnight at room temperature, was inserted into the PVD chamber. Silicon substrates (p-type Si with a resistivity of 1–10 Ω cm [WaferWorld, Inc.]) were cut to size along the (100) crystallographic plane and cleaned by sonicating sequentially in acetone, isopropanol, and methanol for 10 min each. The native oxide layer was then removed by dipping the Si wafers in a solution of 1 wt% HF for 1 min, followed by rinsing with distilled water and drying with compressed air. The cleaned Si substrates were immediately inserted into the PVD chamber which was subsequently evacuated until a low residual pressure was reached $(10^{-6} \text{ mbar}).$

Thin films (Ti or Ti–Sn) of $\sim 1.5~\mu m$ thickness were deposited by cathodic sputtering onto the mirror-polished Si wafers. The substrates were constantly rotated (360°) during the deposition to ensure a uniform thin film composition. An ultrapure Ar atmosphere was maintained inside the chamber at a pressure of 6×10^{-4} mbar during the deposition, with a current of 150 mA. For the Ti–Sn thin film, Ti was first deposited for 30 min to obtain a barrier layer on the silicon substrate for galvanostatic experiments. Anodization experiments were carried out by applying a constant voltage of 40 V during 1.5 h in a conventional two electrode cell using an EG&G PARSTAT 2273 potentiostat/

galvanostat. The thin films (Ti or Ti–Sn) were the working electrodes while a platinum foil served as a counter electrode. The electrodes were separated by a distance of 3 cm and the electrolyte was a solution of 88.7 wt% glycerol, 1.3 wt% NH₄F and 10 wt% H₂O.

Optional thermal treatments at 450 °C were performed in air during 3 h. X-ray-diffraction studies were carried-out at room temperature with a step-time of 10 s and step-size of 0.02° using a Siemens D5000 diffractometer with Cu K α radiation ($\lambda=1.5406~\mbox{Å}$). Scanning Electron Microscope (SEM) images were recorded with a Philips XL-30 FEG SEM. Mott—Schottky analysis was carried out in a 0.1 M Na₂SO₄ solution using an Ag/AgCl reference electrode, a platinum foil counter electrode and the nanotubes as working electrodes. The potential was changed in 0.1 V voltage steps and the impedance was determined at 30 Hz fixed frequency with 10 mV a.c. amplitude using an EG&G PARSTAT 2273 potentiostat/galvanostat.

¹¹⁹Sn room temperature Mössbauer spectra were recorded in the constant acceleration mode and Conversion Electron Mössbauer Spectroscopy (CEMS) geometry. A specific helium-flow counter was used for the detection of conversion electrons. The γ -ray source consisted of Ba^{119m}SnO₃ with a nominal activity of 7 mCi. The hyperfine parameters, isomer shift (δ) and quadrupole splitting (Δ), were determined by fitting appropriate Lorentzian lines to the experimental data. The quality of the fit was controlled by the usual χ^2 -test. All isomer shifts for Sn are given relative to BaSnO₃ at room temperature.

XPS measurements were carried out with a Kratos Axis Ultra spectrometer, using focused monochromatized Al Ka radiation ($h\nu = 1486.6 \text{ eV}$). The XPS spectrometer was directly connected to an argon dry box through a transfer chamber, to avoid moisture/air exposure of the samples. The analysed area of the samples was 300 $\mu m \times 700 \mu m$. Peaks were recorded with a constant pass energy of 20 eV. The pressure in the analysis chamber was around 5×10^{-8} Pa. Short acquisition time spectra were recorded before and after each normal experiment to check that the samples did not suffer from degradation under the X-ray beam during measurements. Peak assignments were made with respect to experimental reference compounds, namely bulk anatase and/or rutile TiO₂. The binding energy scale was calibrated from hydrocarbon contamination using the C1s peak at 285.0 eV. Core peaks were analysed using a non-linear Shirley-type background. The peak positions and areas were optimized by a weighted least-square fitting method using 70% Gaussian and 30% Lorentzian line-shapes. Quantification was performed on the basis of Scofield's relative sensitivity factors.

For the electrochemical measurements, two-electrode Swagelok-type cells were assembled in a glove-box filled with purified argon in which moisture and oxygen contents were less than 2 ppm. The galvanostatic experiments were then carried out with the prepared Li/LiPF₆ (EC:DEC)/ W_E (Working electrode) cells using a VersaSTAT 3 potentiostat/galvanostat. The electrolyte supplied by Merck was embedded in a Whatman glass microfiber, which acts as a separator. It is remarkable to note that additives such as poly(vinyl difluoride) that is a binding agent, and carbon black (conductive agent) were not utilized. For the discharge/charge, a constant current density of $70~\mu A~cm^{-2}$ (1C) was applied to the assembled cells in the $1.0 \le U/V \le 2.6$ voltage range. Additionally, cyclic voltammetry was carried out with the VersaSTAT 3 potentiostat/galvanostat in the $0.65 \le U/V \le 3$ voltage range at a scan rate of $0.1~mV~s^{-1}$.

3. Results and discussion

3.1. Morphology, composition and structure

Fig. 1 shows the current transients recorded during the anodization of Ti and Ti–Sn thin films in an electrolyte consisting of 88.7 wt% glycerol, 1.3 wt% NH₄F and 10 wt% H₂O. It can clearly be

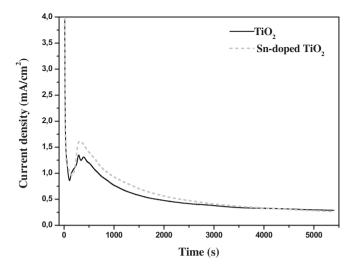


Fig. 1. Chronoamperometric curves obtained during the anodization of Ti and Ti–Sn thin films at 40 V in an electrolyte consisting of 88.7 wt% glycerol, 1.3 wt% NH_4F and 10 wt% H_7O .

noticed that both thin films exhibit the current-transient profile characteristic of nanotubes formation [13,32,33], that is, there is a sharp drop in the anodization current in the first 100 s due to the formation of an initial insulating oxide layer followed by an increase in the current due to the formation of pits in the oxide by a chemical dissolution effect of fluoride ions and the concomitant increase in surface area. The current then decreases as the pits grow into uniformly-spread pores over the surface and increase diffusion length for the reacting ionic species. Finally, the pores grow into nanotubes when the current becomes almost constant as a result of a competition between electrochemical oxide formation and chemical dissolution. The only drastic variation is that the Sn incorporation led to higher peak current values from t=400 to t=3000 s, and this can be explained as a consequence of the formation of smaller diameter Sn-doped TiO₂ nanotubes.

The SEM images of the resulting nanotubes of TiO_2 and $Sndoped\ TiO_2$ are given in Fig. 2. It can be emphasized that the silicon substrates were not heated during the sputtering process. Although the XRD patterns of sputtered Ti thin films previously studied [13,34,35] correspond to hexagonal titanium (JCPDS: 44-1294), we have recently reported that the Ti–Sn thin film corresponds to Sn_3Ti_5 intermetallic [29] (JCPDS: 3-65-3605). The formation of the Sn_3Ti_5 intermetallic is not unusual according to the Hume-Rothery rules, and by anodization under the same conditions as those adopted for the production of the TiO_2 nanotubes

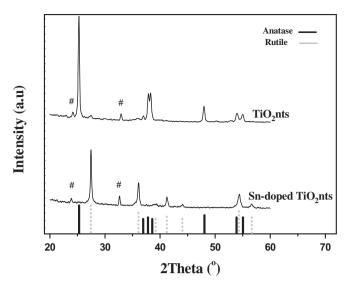


Fig. 3. X-ray diffractograms of TiO_2nts and Sn-doped TiO_2nts recorded after thermal treatments at 450 °C. The low intensity peaks marked '#' are emanating from the silicon substrate.

(Fig. 2b), highly-ordered Sn-doped TiO_2 nanotubes (Fig. 2a) were obtained.

We have already demonstrated the possibility to grow Sn-doped TiO2 nanotubes by anodization of Ti–Sn thin films in aqueous electrolytes (1 M $H_3PO_4, 1$ M NaOH and 0.4 wt% HF) [29]. Compared with these previous results, the morphology of the nanotubes is strongly influenced by the viscosity of the electrolyte as well as the content of water. As shown in Fig. 2, the undoped TiO2 nanotubes have lengths of $\sim 1.4~\mu m$, diameters of $\sim 160~nm$, and sidewall thickness of $\sim 20~nm$; whilst the Sn-doped TiO2 nanotubes have lengths of $\sim 1.2~\mu m$, diameters of $\sim 120~nm$, and sidewall thickness of $\sim 15~nm$.

Fig. 3 shows X-ray diffractograms of the nanotubes recorded after thermal treatments at 450 °C. It can be noticed that whilst the TiO₂nts crystallize (after the thermal treatment) in the anatase structure (JCPDS: 21-1272) with an infinitesimal rutile proportion (JCPDS: 21-1276), the Sn-doped TiO₂nts are transformed entirely into a rutile-type structure (JCPDS: 21-1276) without any traces of SnO₂ (cassiterite) nor SnO (romarchite). This transformation from anatase to rutile observed for the Ti_{1-x}Sn_xO₂-type nanotubes is consistent with the already established fact that Sn⁴⁺ substitution for Ti⁴⁺ in TiO₂ is generally accompanied by the structural transformation from anatase to rutile except for very low ($x \le 0.05$) Sn contents [36,37].

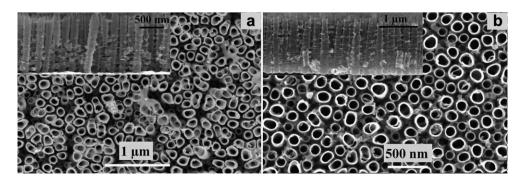


Fig. 2. SEM images of (a) Sn-doped TiO_2 nanotubes (Inset: cross-section), and (b) undoped TiO_2 nanotubes (Inset: cross-section) prepared at 40 V in the electrolyte consisting of 88.7 wt% glycerol, 1.3 wt% NH₄F and 10 wt% H₂O.

In order to confirm the oxidation state of the Sn dopants and ascertain the degree of the doping, X-ray photoelectron spectroscopy was carried out on the as-prepared TiO₂ nanotubes (analysed for comparison) and Sn-doped TiO₂ nanotubes. The obtained high-resolution Ti2p, O1s, C1s and Sn3d XPS core peaks are presented in Figs. 4 and 5. The corresponding data and quantitative analysis are given in Table 1. For both samples, carbon contamination was detected (arising from the traces of the solvent used for the anodization).

For the as-prepared TiO_2 nanotubes, the C1s spectrum presents one main component located at 285.0 eV, associated with C–C or C–H bonds; and two other components at about 286.5 and 288.9 eV, attributed to C–O and O=C–O bonds respectively. Quite similar attributions can be done for the Sn-doped TiO_2 nanotubes, except a very low intensity component located at a high binding energy (289.7 eV), which could correspond to a very low quantity of carbonate species. Due to spin-orbit coupling for both samples, each spectrum exhibits two main Ti2p components located at 459.0 eV ($Ti2p_{3/2}$) and 464.7 eV ($Ti2p_{1/2}$). These binding energies (B.E) are representative of Ti^{4+} in an oxygen environment, which is in agreement with previous XPS data for bulk and thin film TiO_2 [38–42].

In addition, the spectra also contain distinct charge-transfer satellite peaks at about 13 eV above the $2p_{3/2}$ and $2p_{1/2}$ main peak positions. The origin of Ti2p satellite peaks is under debate [43–47]; one of the most likely explanations is the strong covalent hybridization between the metal d and the oxygen p orbitals [43]. The main peaks are essentially characterized by the well screened final state configuration: $2p^53d^1L^{-1}$, where L denotes the ligand electron [44]. The satellite peaks are caused by the hole—particle pair "shake-up" excitation on the anions in the presence of the ligand—metal charge transfer screened core hole. They mostly correspond to the final state configurations $2p^5d^0$ and $2p^5d^1L^{-1}L'L''^{-1}$ [45].

For both samples, the O1s core peaks also present three components. The first one, located at 530.4(5) eV, is assigned to oxygen atoms of the TiO_2 oxide lattice. Hence, it can be noted from Table 1 that for the as-prepared undoped TiO_2 nanotubes, the O/Ti atomic ratio is close to 2 (37.6/19.3); and for the as-prepared Sndoped TiO_2 nanotubes, the O/(Ti+Sn) atomic ratio is also close to 2 (39.7/22.3). Certainly, the two other O1s core peaks (531.7 and 532.8 eV) are related to O=C-O and C-O bonds from solvent traces, in agreement with C1s core peaks. Obviously, the Sn doping does not seem to affect the ionic network of titanium dioxide nanotubes, as no substantial modifications of binding energies were observed. Owing to spin-orbit coupling effects, two peaks corresponding to $Sn3d_{5/2}$ (487.1 eV) and $Sn3d_{3/2}$ (495.5 eV), are

observed, which are ascribable to Sn^{4+} incorporated into the TiO_2 lattice [48,49]. The quantity of the Sn dopants (x) in the $\mathrm{Ti}_{1-x}\mathrm{Sn}_x\mathrm{O}_2$ -type nanotubes was estimated to be \sim 0.5, since a Ti/Sn ratio of \sim 1 was obtained (Table 1).

Fig. 6a—c presents the ¹¹⁹Sn Mössbauer spectra of the Ti—Sn thin film, and the Sn-doped TiO2nts before and after annealing at 450 °C for 3 h. All these spectra were obtained under the same conditions. A summary of the obtained hyperfine parameters is given in Table 2. The parameters ($\delta = 1.688(8) \text{ mm s}^{-1}$; $\Delta = 0.47(2) \text{ mm s}^{-1}$) obtained for the signal of the Ti-Sn thin film (Fig. 6a) can be attributed to Sn⁰, emphasizing that the sputtering process led to pure metallic products. Moreover, the weak line width (2Γ) of the Sn⁰ signal is consistent with the XRD results that the Ti–Sn thin film does not consist of a mixture of phases. Although the starting Ti-Sn thin film corresponds (according to X-ray Diffraction) to Sn₃Ti₅ intermetallic as mentioned earlier, the ¹¹⁹Sn Mössbauer spectroscopy studies could not confirm the exact nature of this thin film as the hyperfine parameters did not exactly match those of Ti-Sn intermetallics previously reported [50,51]. However, Ti₂Sn $(\delta = 1.76 \text{ mm s}^{-1})$, Ti₃Sn $(\delta = 1.80 \text{ mm s}^{-1})$ and Ti₅Sn₃ $(\delta = 1.81 \text{ mm s}^{-1})$ have isomer shifts close to what was obtained for our Ti-Sn thin film although the quadrupole splitting of the former intermetallics were more intense [50,51]. It is important to note that the intermetallics mentioned in literature, apart from having particulate morphologies, were produced by arc melting and annealed at very high temperatures. In addition, XRD evidenced the presence of impurity phases [50,51]. Thus the mismatch in the hyperfine parameters in comparison to the present results can be explained by the differences in synthesis routes, thermal treatments, morphologies, and purity of the crystalline phases.

The spectrum of the as-prepared Sn-doped TiO2nts (Fig. 6b) consists of two unresolved doublets. The doublet at $\delta = 1.66(3) \text{ mm s}^{-1}$ is attributed to the Sn⁰ from the remaining Ti– Sn layer that has not been anodized. Although the presence of this un-anodized Ti-Sn layer was not revealed by XRD, it can be due to the fact that, most probably, the amount of the remaining Ti-Sn layer is below the detection limit of XRD. This is consistent with the undoped TiO₂ nanotubes; the presence of un-anodized Ti layer was also not revealed by XRD. The other doublet at $\delta = 0.06(2) \text{ mm s}^{-1} \text{ can be ascribed to Sn(IV)}$. The isomer shift of $\delta = 0.06(2)$ is very close to what is typically obtained for Sn(IV) bonded to oxygen in octahedral environments [52-54]. These Mössbauer parameters are also in good agreement with those previously [55] obtained for Sn-doped anatase TiO₂ particles. The structural and chemical characterization performed by XRD, XPS, and Mössbauer spectroscopy clearly confirm the octahedral substitution of Sn⁴⁺ for Ti⁴⁺ in the self-organized TiO₂ nanotubes.

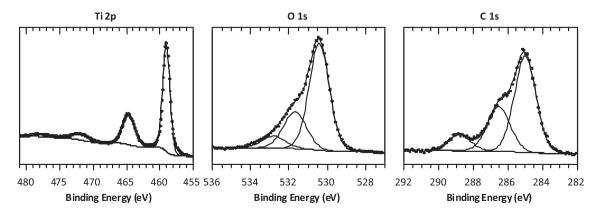


Fig. 4. High-resolution Ti2p, O1s and C1s XPS spectra for the as-prepared TiO₂ nanotubes.

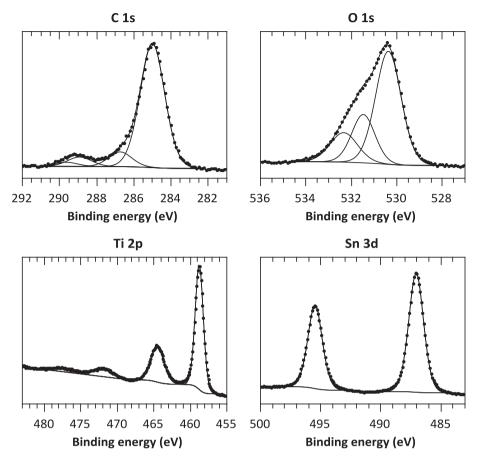


Fig. 5. High-resolution Ti2p, O1s, C1s and Sn3d XPS spectra for the as-prepared Sn-doped TiO₂ nanotubes.

When the Sn-doped TiO_2 nts sample is annealed (Fig. 6c), two modifications are observed: (i) the intensity of the emission signal increased, indicating that annealing induced an increase in crystallite size; and (ii) the quadrupole splitting of the Sn^{4+} doublet decreased, indicating a better ordered lattice for the annealed sample. The relative amounts of Sn^0 and Sn^{4+} were not significantly affected by the heat treatment. Moreover, the Sn^0 doublet has the

Table 1Binding energies, full widths at half maximum (FWHM) and atomic percentages of Ti2p, O1s, C1s and Sn3d XPS core peaks for the as-prepared $\rm TiO_2$ and Sn-doped $\rm TiO_2$ nanotubes. The italicized numbers are the total at% of the contributions to the different core peaks.

Core peaks	TiO ₂			Sn-doped TiO ₂		
	B.E. (eV)	FWHM	at%	B.E. (eV)	FWHM	at%
C1s	285.0	1.4	18.3	285.0	1.5	21.8
	286.5	1.5	6.3	286.6	1.5	3.7
	288.8	1.5	2.8	288.9	1.5	2.8
				289.8	1.5	0.8
			27.4			29.1
Ti2p	459.0	1.3	10.9	458.8	1.3	6.6
	464.7	2.2	5.8	464.5	2.1	3.1
	471.9	3.2	1.8	472.0	3.2	1.0
	477.6	3.4	0.8	477.5	3.0	0.4
			19.3			11.1
O1s	530.4	1.2	37.6	530.5	1.2	39.7
	531.7	1.4	11.4	531.6	1.3	7.0
	532.8	1.4	4.5	532.7	1.4	4.4
			53.3			49.1
Sn3d				487.1	1.4	6.7
				495.5	1.4	4.5
						11.2

same parameters as those obtained for the as-prepared Sn-doped ${\rm TiO_2}$ nts sample and the as-sputtered ${\rm Ti-Sn}$ thin film, indicating that the structure of the ${\rm Ti-Sn}$ thin film is conserved for all samples.

3.2. Electronic properties

From the Mott–Schottky equation given in Eq. (1), the flat band potential (E_{fb}) and the charge carrier concentration (N_D) of a specific semiconductor can be determined by plotting C^{-2} versus E (potential).

$$\frac{1}{C^2} = \left(\frac{2}{q \,\varepsilon_{\rm E} \rho N_{\rm D}}\right) \left(E - E_{\rm fb} - \frac{kT}{q}\right) \tag{1}$$

Where C is the capacitance of the space charge layer; q the elementary charge (1.6 \times 10⁻¹⁹ C); ε_0 the vacuum permittivity (8.85 \times 10⁻¹⁴ F cm⁻¹); ε the dielectric constant of the studied semiconductor; k is Boltzmann's constant; and T is the absolute temperature. Fig. 7 shows the Mott–Schottky plots obtained for the undoped and the Sn-doped TiO₂nts. The positive slope of each plot is in agreement with n-type semi-conductivity. In principle, TiO₂ tends to be oxygen-deficient at ambient temperature and pressure, making the material an n-type semiconductor according to the defect equilibrium given below in Kröger–Vink notation:

$$O_0 \rightarrow V_0$$
" + $\frac{1}{2}O_2 + 2e'$ (2)

For both undoped and Sn-doped TiO₂nts, approximately the same values of $E_{\rm fb}$ (-0.85 V vs Ag/AgCl) and N_D (6.5×10^{19} cm $^{-3}$)

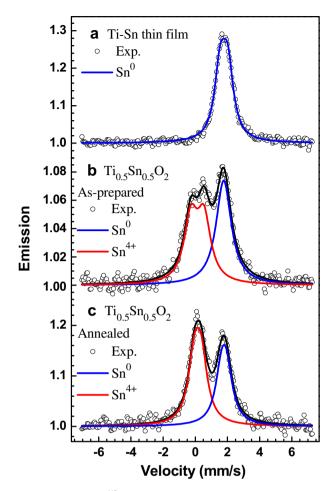


Fig. 6. Room temperature 119 Sn Mössbauer spectra recorded for as-deposited Ti–Sn thin film (a), and Sn-doped TiO₂nts (b: amorphous, c: annealed at 450 °C).

were estimated, which is consistent with the theoretical consideration that $\mathrm{Sn^{4+}}$ substitution for $\mathrm{Ti^{4+}}$ (isovalent) in $\mathrm{TiO_2}$ should not modify the semi-conducting behaviour.

The conductivity (σ) of either the undoped or the Sn-doped TiO₂nts can be estimated using the charge carrier concentration (N_i) , the electron mobility (μ_i) and the elementary charge (q_i) according to Eq. (3) [56,57]; but the resulting values should be indistinguishable as the same values of charge carrier concentration (N_i) were obtained from the Mott–Schottky analysis.

$$\sigma_i = q_i \mu_i N_i \tag{3}$$

However, it has previously [36] been demonstrated that $\rm Sn^{4+}$ substitution for $\rm Ti^{4+}$ in $\rm TiO_2$ leads to increase of the bond lengths of the inner coordination shells due to the larger ionic radius of $\rm Sn^{4+}$

Table 2Room temperature ¹¹⁹Sn Mössbauer hyperfine parameters obtained from Ti—Sn thin film, as-prepared and annealed Sn-doped TiO₂nts.

Sample	Attribution	δ (mm/s)	Δ (mm/s)	2Γ (mm/s)	C (%)	χ^2
Ti-Sn thin film	Sn ⁰	1.688(8)	0.47(2)	0.84(2)	100	0.42
As-prepared	Sn ⁰	1.66(3)	0.36(6)	0.98(7)	46(8)	0.46
Sn-doped TiO ₂ nt	Sn ⁴⁺	0.05(2)	0.81(2)	1.02(5)	54(6)	
Annealed	Sn ⁰	1.69(2)	0.32(8)	0.91(6)	43(1)	0.51
Sn-doped TiO ₂ nt	Sn ⁴⁺	0.06(2)	0.42(5)	0.91(6)	57(1)	

 δ : isomer shift; Δ : quadrupole splitting; 2Γ : full line width at half-maximum; C: contribution to total emission (not corrected due to unknown Lamb–Mössbauer factors); χ^2 : goodness of the fitting.

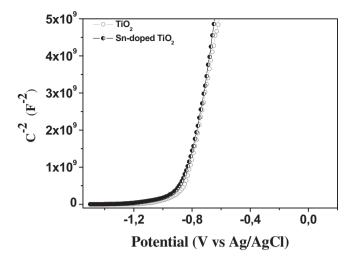


Fig. 7. Mott–Schottky plots obtained for the undoped and the Sn-doped TiO_2 nts in a 0.1 M Na_2SO_4 solution at 30 Hz.

 $[r(Sn^{4+}) = 0.83 \text{ Å}]$ compared to Ti^{4+} $[r(Ti^{4+}) = 0.75 \text{ Å}]$. Fundamentally, increased bond lengths are indicative of weakened bonds and thus migration of cations (Li⁺) is expected to be enhanced in the modified lattice. In view of this, we carried out potentiostatic experiments for which the current-transient profiles before the onset of a limiting current can be described by the Cottrell equation [58,59]:

$$j = nFD_0^{1/2}C_0\pi^{-1/2}t^{-1/2} \tag{4}$$

The potentiostatic experiments consisted of applying a potential step (from 3.0 to 1.4 V vs Li⁺/Li) to cells of Li/LiPF₆ (EC:DEC)/(TiO₂nts or Sn-doped TiO₂nts) during 30 s. Assuming the composition of the initial subsurface layer to be Li_{0.5}TiO₂ for both TiO₂nts and Sn-doped TiO₂nts, the concentration of Li⁺ (C_0) was calculated to be 25×10^{-3} mol cm⁻³ using 4 g cm⁻³ density of TiO₂. Hence, the diffusion coefficients (D_0) were estimated from the slopes of the fits to the Cottrell plots (Fig. 8) to be 1.6×10^{-13} cm² s⁻¹ and 6.7×10^{-12} cm² s⁻¹ for TiO₂nts and Sn-doped TiO₂nts respectively. These values of diffusion coefficients agree with previous reports [58,59] in literature and indicate that Li⁺ insertion into Sn-doped TiO₂nts is about 40 times faster than into undoped TiO₂nts. This is consistent with the assertion that increased bond lengths lead to more easy lithium ion diffusion in the structure.

3.3. Electrochemical behaviour versus lithium

The electrochemical behaviour versus lithium of the Sn-doped TiO2nts was evaluated by galvanostatic cycling experiments and compared to that of undoped TiO2nts as shown in Fig. 9, with a summary also given in Table 3. In spite of the fact that both nanotubes (doped and undoped) were prepared under the same conditions (40 V in a viscous electrolyte consisting of 88.7 wt% glycerol, 1.3 wt% NH₄F and 10 wt% H₂O), the Sn-doped TiO₂nts delivered much higher capacity values. It has already [30,60,61] been established that the reactivity of rutile TiO₂ is sensitive to lithium diffusivity as a result of its peculiar crystal structure, hence the outstanding performance of the Sn-doped TiO₂nts is proposed to be related to the rutile-type structure and the enhanced lithium diffusivity imparted with the Sn doping; it was shown above with Cottrell plots (Fig. 8) that Li⁺ insertion into Sn-doped TiO₂nts is about 40 times faster than into undoped TiO2nts. Also, cycling efficiencies were estimated to be 76%, 85% and 89% (Table 3) for the amorphous TiO2nts, amorphous Sn-doped TiO2nts and crystalline

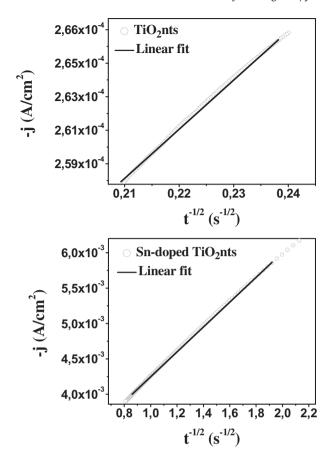


Fig. 8. Cottrell plots for the determination of $\mathrm{Li^+}$ diffusion coefficients in $\mathrm{TiO_2}$ nts and $\mathrm{Sn\text{-}doped\ TiO_2}$ nts.

Sn-doped TiO_2 nts respectively. Cycling efficiency (E) is a measure of capacity retention, and it can be expressed as the ratio of final reversible capacity (Q_f) to initial reversible capacity (Q_f) [13,14]. Generally, amorphous TiO_2 electrodes exhibit lower cycling efficiencies than the crystalline counterparts, since the latter precludes lithium storage into defect sites and side reactions with substantial solvent traces [13]. Also, it can be asserted that so far as TiO_2 electrodes are concerned, cycling efficiencies are somewhat sensitive to current densities (C-rate values) [13].

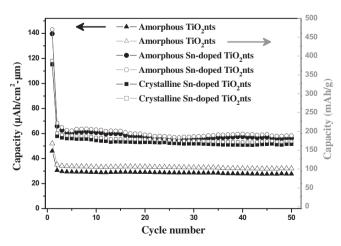


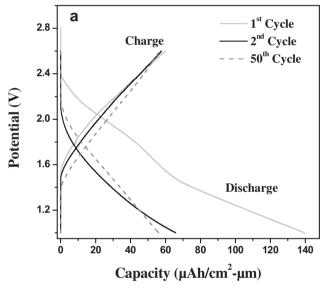
Fig. 9. Galvanostatic cycle life performance at 70 μ A cm⁻² for the undoped and the Sndoped TiO₂nts in the 1.0 \leq U/V \leq 2.6 voltage range. The capacity values are given in μ Ah cm⁻² μ m⁻¹ (closed symbols) and in mAh g⁻¹ (open symbols) for amorphous TiO₂nts and Sn-doped TiO₂nts (amorphous and crystalline).

Table 3 Discharge capacities and cycling efficiencies (capacity retention) with 70 μ A cm⁻² current density.

Electrode	Condition		capacity	50th reversible capacity ($\mu Ah~cm^2~\mu m$)	efficiency
TiO ₂ nts	1-2.6 V	28.6	17.0	21.9	76
Sn-doped TiO ₂ nts	1-2.6 V	65.9	73.9	56.1	85
Sn-doped TiO ₂ nts ^a	1-2.6 V	57.9	57.2	51.6	89

^a Crystalline.

The reaction for the reversible insertion of lithium into TiO₂ is as given in Eq. (5). Although a maximum of 0.5 Li⁺ can be inserted into anatase, rutile can host up to 1 Li⁺ (depending on the cut-off potential) of which almost 0.5 Li⁺ are irreversibly trapped in the structure during the first discharge [14,30]. Due to the degree of the Sn-doping, the Sn-doped TiO₂nts undergo full electrochemical reaction like a rutile-type TiO₂ [29]. That is the reason for the very



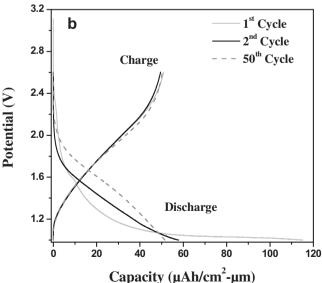


Fig. 10. Galvanostatic curves obtained for the Sn-doped TiO_2nts (a: amorphous, b: crystalline) cycled in the $1.0 \le U/V \le 2.6$ voltage range.

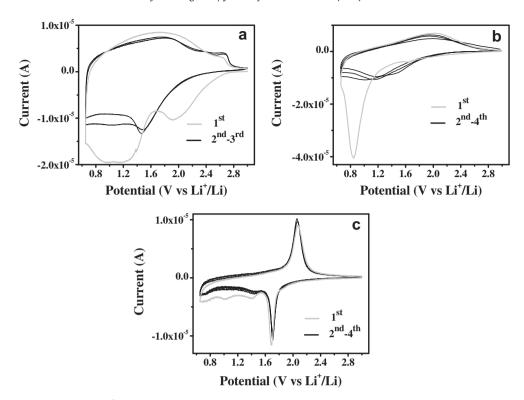


Fig. 11. CV curves recorded at 0.1 mV s⁻¹ in the 0.65 \leq U/V \leq 3 voltage range for Sn-doped TiO₂nts (a: amorphous; b: crystalline), and crystalline TiO₂nts (c).

high first discharge capacities (139.7 μAh cm⁻² μm⁻¹ for amorphous, and 115.1 μ Ah cm⁻² μ m⁻¹ for crystalline) observed for the Sn-doped TiO2nts. It has already been established that despite a very thin or inexistent solid electrolyte interphase (SEI) layer on TiO₂ electrodes, adsorbed solvents on surfaces of amorphous samples or crystallized water in the case of annealed samples contribute to the irreversibility in the first discharge [14]. The pronounced irreverscapacities observed for the Sn-doped TiO₂nts (73.9 μ Ah cm⁻² μ m⁻¹ for amorphous, and 57.2 μ Ah cm⁻² μ m⁻¹ for crystalline) as compared the undoped to $(17.0 \,\mu\text{Ah cm}^{-2} \,\mu\text{m}^{-1})$ are a consequence of the extra lithium-ions irreversibly trapped in the rutile-type structure. The corresponding capacity values in mAh g^{-1} are also presented in Fig. 9.

$$TiO_2 + \chi Li^+ + \chi e^- \leftrightarrow Li_{\chi} TiO_2 \text{ for } 0 < \chi < 1$$
 (5)

The galvanostatic discharge/charge profiles of the Sn-doped TiO2nts (both amorphous and crystalline) are given in Fig. 10; the sloping voltage profiles agree well with the cyclic voltammograms shown in Fig. 11a, b, and are consistent with previous reports in literature [62–64]. For the crystalline Sn-doped TiO2nts, the small plateau at ca. 1.65 V in the first discharge (Fig. 11b) can be attributed to surface storage of lithium, the corresponding small cathodic peak was also evidenced at ca. 1.6 V vs Li⁺/Li in the 1st cycle CV (Fig. 11b). Although the long sloping plateau (in the first discharge) starting at ca. 1.2 V ends at the cut-off potential of 1 V, the CV studies in the $0.65 \leq U/V \leq 3$ voltage range showed that the plateau is actually centred at ca. 0.85 V, and its irreversibility in the subsequent cycles is as a consequence of the extensive lithium storage up to that potential and the concomitant irreversible structural transformations.

The CV obtained from crystalline TiO₂nts (Fig. 11c) was presented to showcase the marked difference in the electrochemical characteristics brought about by the Sn-doping. It is worth noting that amorphous samples of TiO₂-based electrodes generally do not reveal the characteristic peaks of reaction with lithium. The

reduction peak at $ca. 1.7 \text{ V} \text{ vs Li}^+/\text{Li}$ (Fig. 11c) corresponds to lithium insertion (reversible Li⁺ extraction peak at $ca. 2.0 \text{ V} \text{ vs Li}^+/\text{Li}$) into the anatase TiO₂ structure [14,31] and the peaks seen at ca. 1.1 V and 1.4 V $vs \text{ Li}^+/\text{Li}$ (Fig. 11c) correspond to lithium insertion into the infinitesimal proportion of rutile TiO₂ as detected by XRD (Fig. 3) [30,60].

In accounting for the improved behaviour of the Sn-doped TiO_2 nanotubes, it is important to note that the response of only the Sn_3Ti_5 thin-film versus lithium is negligible and besides, the thin film is not active within the cycling voltage range of $1.0 \le U/V \le 2.6$ as it consists mainly of Sn as the active material [16,17,65]. Indeed, it is not the first time a beneficial effect of hetero-atoms is observed on the electrochemical behaviour of anode materials for Li-ion batteries [22,66].

4. Conclusion

Highly-ordered Sn-doped TiO2nts can be produced by anodic oxidation of co-sputtered Ti-Sn thin films in a viscous electrolyte consisting of 88.7 wt% glycerol, 1.3 wt% NH₄F and 10 wt% H₂O. X-ray photoelectron spectroscopy confirmed that the nanotubes are formed by substitution of Sn⁴⁺ for Ti⁴⁺ during the oxide formation, leading to $Ti_{1-x}Sn_xO_2$ -type nanotubes with $x = \sim 0.5$. Due to the degree of the Sn doping, the usual anatase TiO2 nanotubes are transformed into a rutile-type TiO₂ according to X-ray diffraction studies. 119Sn Mössbauer spectroscopy studies confirmed the pure metallic nature of the co-sputtered Ti-Sn thin films and evidenced the octahedral substitution of Sn⁴⁺ for Ti⁴⁺ in the TiO₂ structure as there were no traces of cassiterite (SnO₂) in the material. With current density of 70 μA cm $^{-2}$ (1 C) and cut-off potential of 1 V, Sndoped TiO2nts delivered much higher capacity values as compared to simple TiO₂nts. The outstanding performance is proposed to be related to the enhanced lithium diffusivity evidenced with Cottrell plots, and the rutile-type structure imparted with the Sn doping. The electrochemical studies have demonstrated that ${\rm TiO_2}$ nanotubes indeed have the potential to be employed as anodes for the design of high-performance 3D Li-ion micro batteries. Further characterization such as ex-situ $^{119}{\rm Sn}$ Mössbauer spectroscopy and post-mortem XRD of cycled electrodes would be useful to confirm that the ${\rm Ti_{1-x}Sn_xO_2}$ -type nanotubes indeed undergo lithium insertion as a rutile-type ${\rm TiO_2}$. This novel synthesis approach can be extended for ${\rm Fe/Sb/Nb}$ -doping of on-wafer (Si) ${\rm TiO_2}$ nanotubes due to the usefulness of ${\rm TiO_2}$ nanotubes and the need to tune their intrinsic properties by doping.

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References

- D. Golodnitsky, V. Yufit, M. Nathan, I. Shechtman, T. Ripenbein, E. Strauss, S. Menkina, E. Peled, J. Power Sources 153 (2006) 281–287.
- [2] J.B. Bates, N.J. Dudney, B.J. Neudecker, F.X. Hart, H.P. Jun, S.A. Hackney, J. Electrochem. Soc. 147 (2000) 59.
- [3] K. Kanehori, K. Matsumoto, K. Miyauchi, T. Kudo, Solid State Ionics 9/10 (1983) 1445.
- [4] R.W. Hart, H.S. White, B. Dunn, D.R. Rolison, Electrochem. Commun. 5 (2003) 120–123.
- [5] W. Lai, C.K. Erdonmez, T.F. Marinis, C.K. Bjune, N.J. Dudney, F. Xu, R. Wartena, Y.M. Chiang, Adv. Mater. 22 (2010) E139.
- [6] J.W. Long, B. Dunn, D.R. Rolison, H.S. White, Chem. Rev. 104 (2004) 4463– 4492
- [7] J.B. Bates, N.J. Dudney, K.A. Weatherspoon, US Patent.
- [8] B. Fleutot, B. Pecquenard, F. Le Cras, B. Delis, H. Martinez, L. Dupont, D. Guy-Bouyssou, J. Power Sources 196 (2011) 10289–10296.
- [9] P.H.L. Notten, F. Roozeboom, R.A.H. Niessen, L. Baggetto, Adv. Mater. 19 (2007) 4564—4567.
- [10] Y.J. Park, K.S. Park, J.G. Kim, M.K. Kim, H.G. Kim, H.T. Chung, J. Power Sources 88 (2000) 250–254.
- [11] M. Kotobuki, Y. Suzuki, H. Munakata, K. Kanamura, Y. Sato, K. Yamamotob, T. Yoshida, J. Power Sources 195 5784—5788.
- [12] Z.G. Lu, H. Cheng, M.F. Lo, C.Y. Chung, Adv. Funct. Mater. 17 (2007) 3885—3896.
- [13] G.F. Ortiz, I. Hanzu, P. Knauth, P. Lavela, J.L. Tirado, T. Djenizian, Electrochim. Acta 54 (2009) 4262–4268.
- [14] G.F. Ortiz, I. Hanzu, T. Djenizian, P. Lavela, J.L. Tirado, P. Knauth, Chem. Mater. 21 (2009) 63–67.
- [15] J. Song, M.-Z. Cai, Q.-F. Dong, M.-S. Zheng, Q.-H. Wu, S.-T. Wu, Electrochim. Acta 54 (2009) 2748–2753.
- [16] L. Bazin, S. Mitra, P.L. Taberna, P. Poizot, M. Gressier, M.J. Menu, A. Barnabé, P. Simon, J.M. Tarascon, J. Power Sources 188 (2009) 578–582.
- [17] G.F. Ortiz, I. Hanzu, P. Lavela, P. Knauth, J.L. Tirado, T. Djenizian, Chem. Mater. 22 (2010) 1926—1932.
- [18] G.F. Ortiz, I. Hanzu, P. Knauth, P. Lavela, J.L. Tirado, T. Djenizian, Electrochem. Solid State Lett. 12 (2009) A186—A189.
- [19] P. Poizot, S. Laruelle, S. Grugeon, L. Dupont, J.M. Tarascon, Nature 407 (2000) 496–499.
- [20] L. Taberna, S. Mitra, P. Poizot, P. Simon, J.M. Tarascon, Nat. Mater. 5 (2006)
- [21] G.F. Ortiz, J.L. Tirado, Electrochem. Commun. 13 (2011) 1427–1430.
- [22] P. Lavela, N.A. Kyeremateng, J.L. Tirado, Mater. Chem. Phys. 124 (2010) 102–108.
- [23] M.S. Whittingham, F.R. Gamble, Mater. Res. Bull. 10 (1975) 363–371.
- [24] C. Navone, J.P. Pereira-Ramos, R. Baddour-Hadjean, R. Salot, J. Electrochem. Soc. 153 (2006) A2287–A2293.
- [25] A. Gies, B. Pecquenard, A. Benayad, H. Martinez, D. Gonbeau, H. Fuess, A. Levasseur, Thin Solid Films 516 (2008) 7271–7281.

- [26] N. Plylahan, N.A. Kyeremateng, M. Eyraud, F. Dumur, H. Martinez, L. Santinacci, P. Knauth, T. Djenizian, Nanoscale Res, Lett. 7 (2012) 349.
- [27] N.A. Kyeremateng, F. Dumur, P. Knauth, B. Pecquenard, T. Djenizian, C. R. Chimie (2012). http://dx.doi.org/10.1016/j.crci.2012.05.002.
- [28] N.A. Kyeremateng, F. Dumur, P. Knauth, B. Pecquenard, T. Djenizian, Electrochem. Commun. 13 (2011) 894–897.
- [29] N.A. Kyeremateng, V. Hornebecq, P. Knauth, T. Djenizian, Electrochim. Acta 62 (2012) 192–198.
- [30] P. Kubiak, M. Pfanzelt, J. Geserick, U. Hörmann, N. Hüsing, U. Kaiser, M. Wohlfahrt-Mehrens, J. Power Sources 194 (2009) 1099–1104.
- [31] T. Dienizian, I. Hanzu, P. Knauth, I. Mater, Chem. 21 (2011) 9925-9937.
- [32] D. Gong, C.A. Grimes, O.K. Varghese, W.C. Hu, R.S. Singh, Z. Chen, E.C. Dickey, J. Mater. Res. 16 (2001) 3331–3334.
- [33] J.M. Macak, H. Tsuchiya, A. Ghicov, K. Yasuda, R. Hahn, S. Bauer, P. Schmuki, Curr. Opin. Solid State Mater. Sci. 11 (2007) 3–18.
- [34] Y.D. Premchand, T. Djenizian, F. Vacandio, P. Knauth, Electrochem. Commun. 8 (2006) 1840–1844.
- [35] T. Djenizian, I. Hanzu, Y.D. Premchand, F. Vacandio, P. Knauth, Nanotechnology 19 (2008) 205601.
- [36] A. Weibel, R. Bouchet, S.L.P. Savin, A.V. Chadwick, P.E. Lippens, M. Womes, P. Knauth, ChemPhysChem 7 (2006) 2377–2383.
- [37] F. Fresno, D. Tudela, J.M. Coronado, J. Soria, Catal. Today 143 (2009) 230–236.
- [38] M.G. Faba, D. Gonbeau, G. Pfisterguillouzo, J. Electron. Spectrosc. 73 (1995) 65–80
- [39] J.-C. Dupin, D. Gonbeau, P. Vinatier, A. Levasseur, Phys. Chem. Chem. Phys. 2 (2000) 1319–1324.
- [40] C. Guimon, A. Gervasini, A. Auroux, J. Phys. Chem. B 105 (2001) 10316–10325.
- 41] A.R. Gonzalezelipe, G. Munuera, J.P. Espinos, J.M. Sanz, Surf. Sci. 220 (1989) 368–380.
- [42] M.C. Biesinger, L.W.M. Lau, A.R. Gerson, R.S.C. Smart, Appl. Surf. Sci. 257 (2010) 887–898.
- [43] J.C. Parlebas, M.A. Khan, T. Uozumi, K. Okada, A. Kotani, J. Electron. Spectrosc. 71 (1995) 117—139.
- [44] J.L. Guimaraes, M. Abbate, S.B. Betim, M.C.M. Alves, J. Alloy. Compd. 352 (2003) 16–20
- [45] D.K.G. Deboer, C. Haas, G.A. Sawatzky, Phys. Rev. B 29 (1984) 4401–4419.
- 46] I. Pollini, A. Mosser, J.C. Parlebas, Phys. Rep. 355 (2001) 1–72.
- [47] A.E. Bocquet, T. Mizokawa, K. Morikawa, A. Fujimori, S.R. Barman, K. Maiti, D.D. Sarma, Y. Tokura, M. Onoda, Phys. Rev. B 53 (1996) 1161–1170.
- [48] X.J. Zhu, Z.P. Guo, P. Zhang, G.D. Du, C.K. Poh, Z.X. Chen, S. Li, H.K. Liu, Electrochim. Acta 55 (2010) 4982–4986.
- [49] X. Zhou, W. Fu, H. Yang, D. Ma, J. Cao, Y. Leng, J. Guo, Y. Zhang, Y. Sui, W. Zhao, M. Li, Mater. Chem. Phys. 124 (2010) 614–618.
- [50] J.W. O'Brien, R.A. Dunlap, J.R. Dahn, J. Alloy. Compd. 353 (2003) 60-64.
- [51] J.W. O'Brien, R.A. Dunlap, J.R. Dahn, J. Alloy. Compd. 353 (2003) 65-73.
- [52] B. Grzeta, E. Tkalcec, C. Goebbert, M. Takeda, M. Takahashi, K. Nomura, M. Jaksic, J. Phys. Chem. Solids 63 (2002) 765–772.
- [53] V.S. Urusov, D.A. Khramov, K. Langer, Eur. J. Mineral. 11 (1999) 295-298.
 - I. Issac, M. Scheuermann, S.M. Becker, E.G. Bardaji, C. Adelhelm, D. Wang, C. Kuebel, S. Indris, J. Power Sources 196 (2011) 9689–9695.
- [55] L. Aldon, P. Kubiak, A. Picard, J.C. Jumas, J. Olivier-Fourcade, Chem. Mater. 18 (2006) 1401–1406.
- [56] L.V. Taveira, A.A. Saguees, J.M. Macak, P. Schmuki, J. Electrochem. Soc. 155 (2008) C293—C302.
- [57] I. Hanzu, T. Djenizian, P. Knauth, J. Phys. Chem. C 115 (2011) 5989-5996.
- [58] I. Hanzu, T. Djenizian, G.F. Ortiz, P. Knauth, J. Phys. Chem. C 113 (2009) 20568–20575.
- [59] L. Kavan, M. Grätzel, S.E. Gilbert, C. Klemenz, H.J. Scheel, J. Am. Chem. Soc. 118 (1996) 6716–6723.
- [60] M. Pfánzelt, P. Kubiak, M. Fleischhammer, M. Wohlfahrt-Mehrens, J. Power Sources 196 (2011) 6815–6821.
- [61] W.J. Macklin, R.J. Neat, Solid State Ionics 53-56 (1992) 694-700.
- [62] H. Uchiyama, E. Hosono, H. Zhou, H. Imai, Solid State Ionics 180 (2009) 956–960.
- [63] S. Dong, H. Wang, L. Gu, X. Zhou, Z. Liu, P. Han, Y. Wang, X. Chen, G. Cui, L. Chen, Thin Solid Films 519 (2011) 5978–5982.
- [64] J.S. Chen, X.W. Lou, J. Power Sources 195 (2010) 2905-2908.
- [65] G.F. Ortiz, P. Lavela, P. Knauth, T. Djenizian, R. Alcantara, J.L. Tirado, J. Electrochem. Soc. 158 (2011) A1094—A1099.
- [66] M.J. Aragon, B. Leon, T. Serrano, C.P. Vicente, J.L. Tirado, J. Mater. Chem. 21 (2011) 10102–10107.